



SW Test Workshop

Semiconductor Wafer Test Workshop

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Blindmate RF Connector for E-Band Production Test



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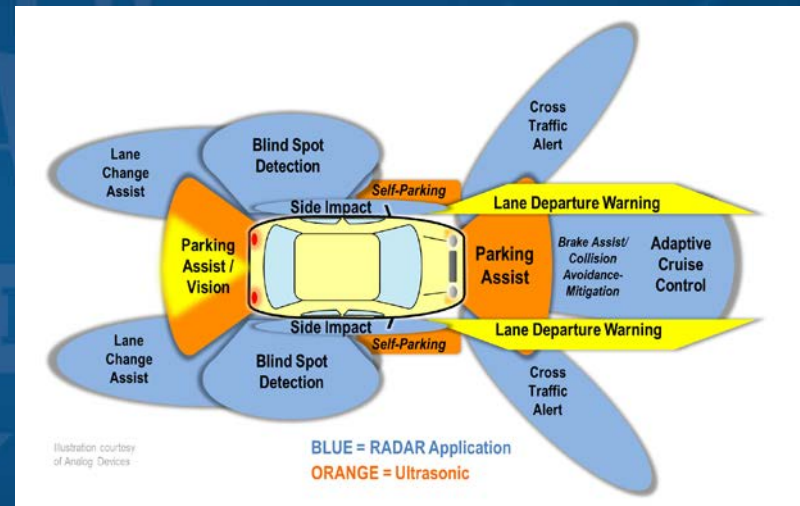
Overview

- **Introduction**
- **Production E-Band test (60-90 GHz)**
 - Current Connector Options and Limitations
- **Summary of Connectors for production test**
- **Performance comparison with non-Blindmate connectors**
- **Summary**

E-Band Market Drivers

- There are several primary market drivers that are requiring more test in the E-band

- Automotive Radar



- 802.11ad

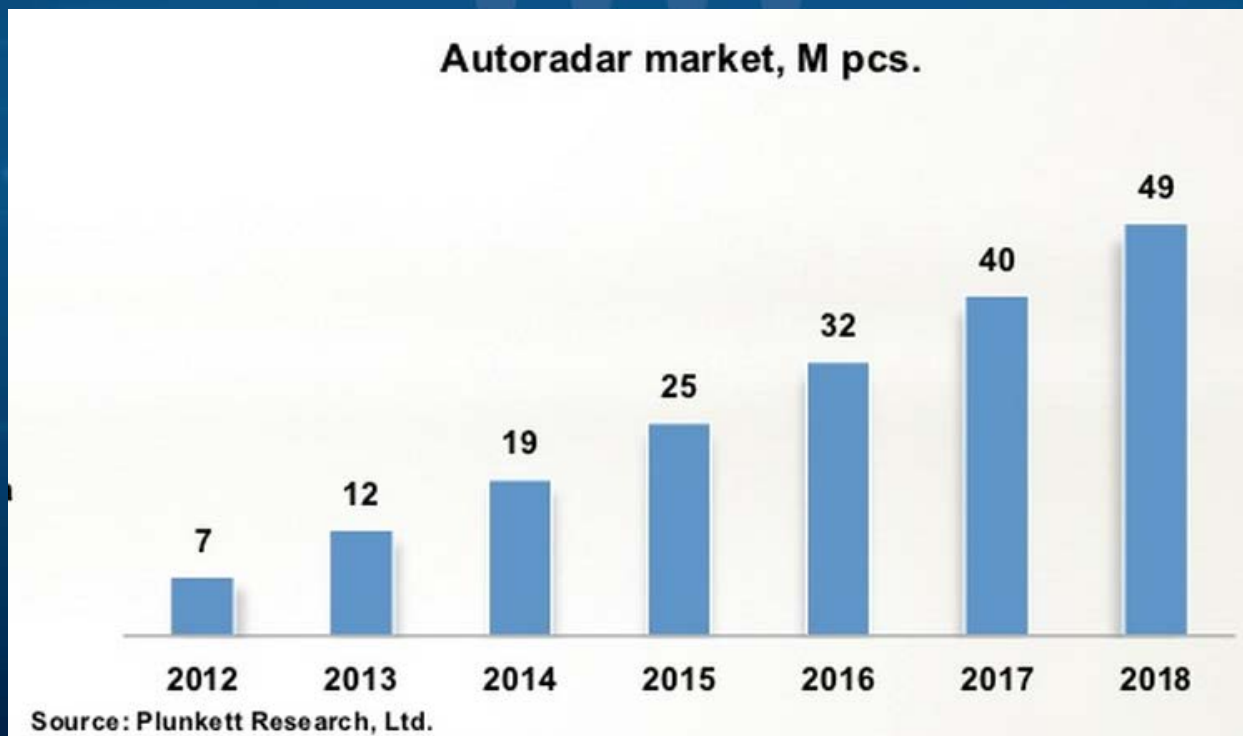


- Cell Phone Short/Back Haul



Market Growth Coming

- **The largest of these is projected to be Automotive Radar**
 - An anticipated CAGR of ~33% through 2018








What does this mean for Probe Cards?

- **The market will require:**
 - Hard dock probe cards instead of cabled (soft dock)
 - Prefer blind-mate connectors to standard coax connectors
 - Large number of RF connectors
 - Each automotive die can have 5+ RF high speed channels
 - x4 would then require more than 20 RF connectors per probe card

What should a full production connector look like?

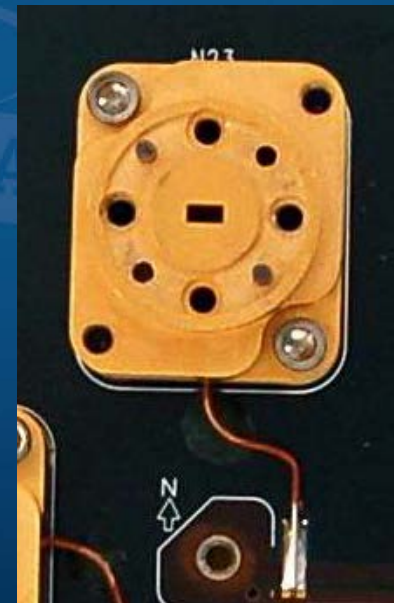
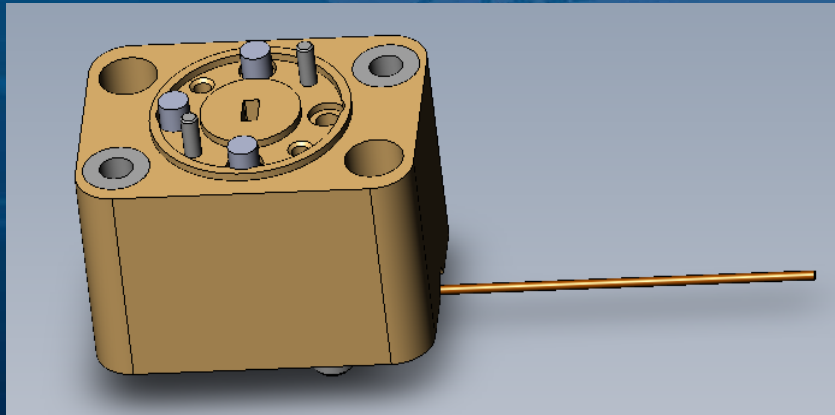
- **Simple to connect**
 - Requires no manual 'threading'
- **Minimize need for recalibration**
 - No flexing of coax
- **No need for the test engineer to install the probe card**
- **High performance (better than -10 dB RL)**
 - Air dielectric is preferred

Current Types of Connectors for above 40 GHz

Connector	BW	Type of Connector	Example	Limitations
1.85 mm	67 GHz	Thread-on		Soft Dock
1 mm	110 GHz	Thread-on		Soft Dock
SMPM	65 GHz	Blindmate		Not enough BW
SMPS	100 GHz	Blindmate		Low number of cycles (<500)
SSB	65 GHz	Blindmate		Not enough BW

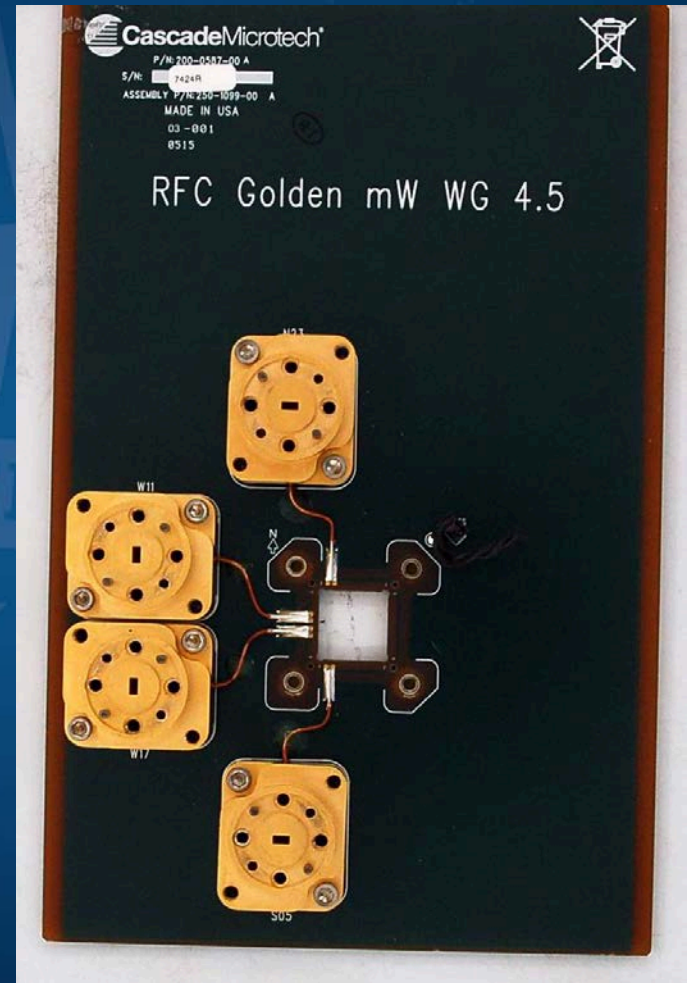
Direct-dock Waveguide Connector

- In order to meet the requirements for a full production connector, Cascade Microtech is developing a Blind-mate Waveguide connector



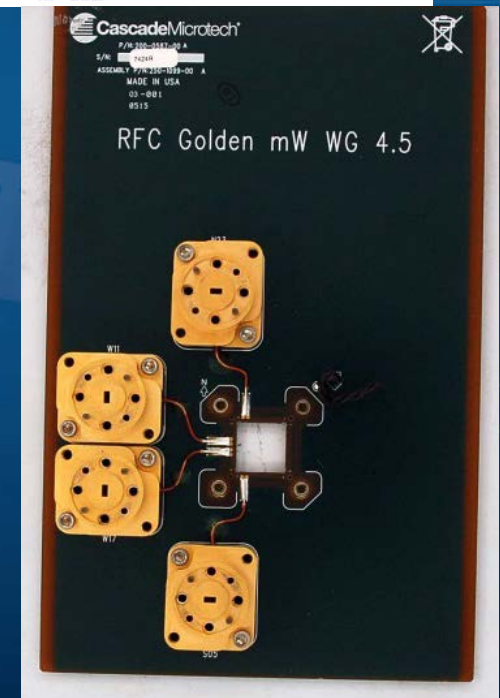
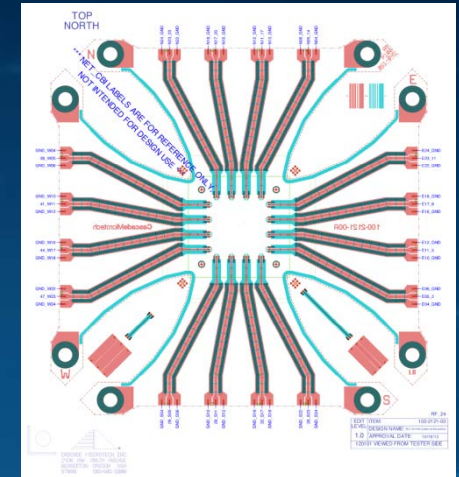
Evaluation Probe card

- Cascade Microtech fabricated an evaluation probe card to test RF performance when using a Pyramid Probe®
 - The evaluation Probe card had 4 waveguide connectors
 - 4.5" probe card
 - Used the smallest Pyramid Probe (RFC)



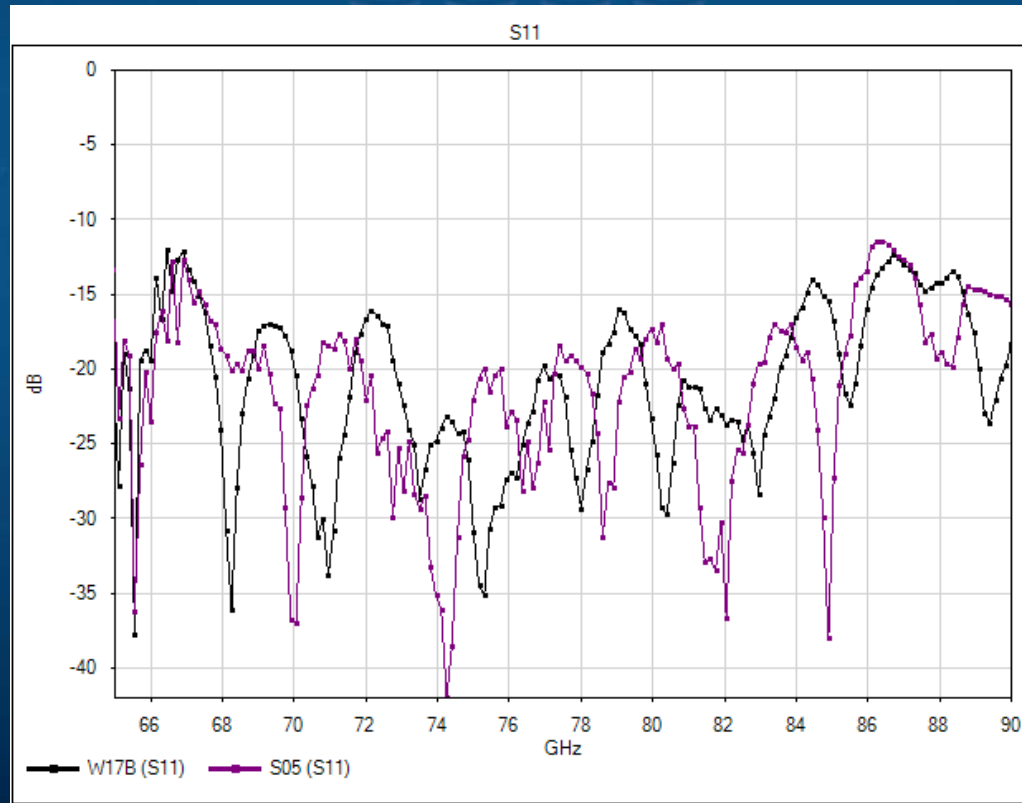
Test Setup

- **A Golden Pyramid Probe**
 - Designed for 80 GHz performance
- **PCB using Blindmate Waveguide**
 - Semi-rigid 0.031" coax between the waveguide and the Pyramid Probe
- **Cascade Microtech Summit 12k Probe Station**
- **Keysight E8361C with frequency extenders**
 - Using Coax to waveguide adapters (WR12)



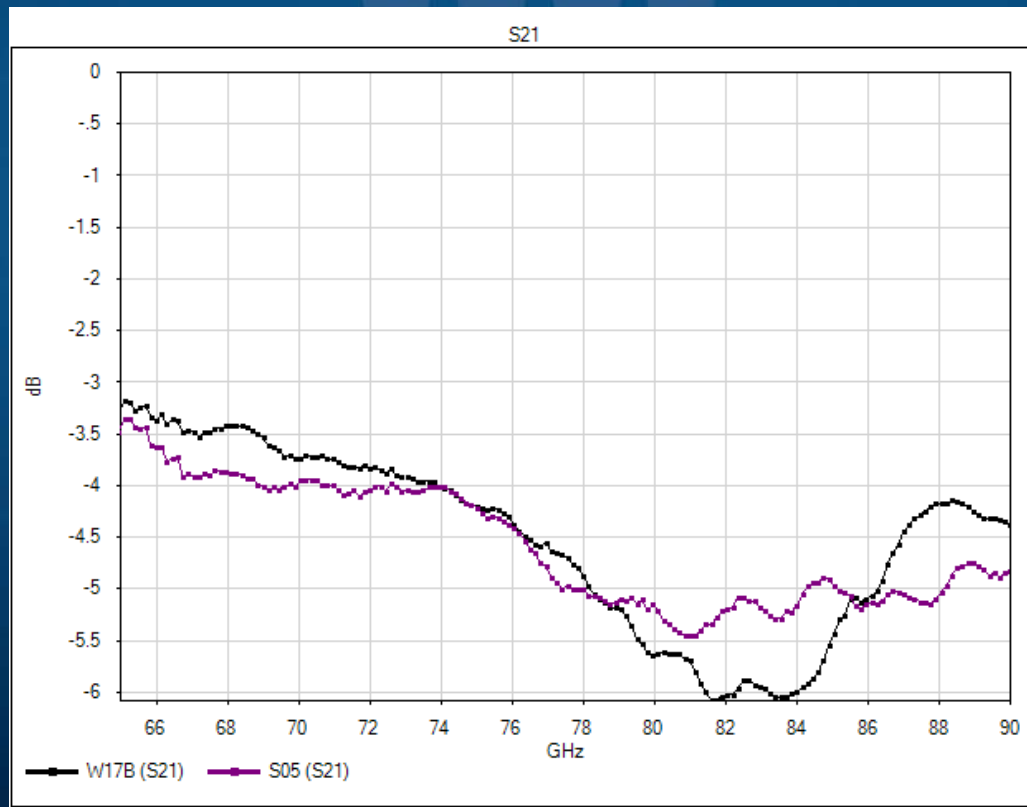
RF Data – Return Loss

- **Better than -10 dB from 65 GHz to 90 GHz**
 - Better than -15 dB from 68 to 84 GHz



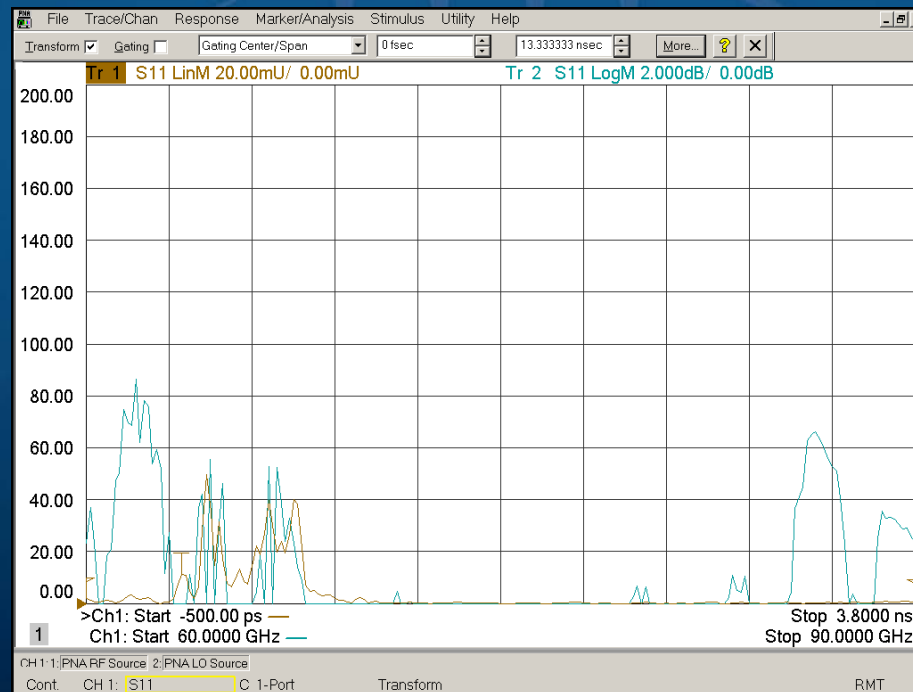
RF Data – Insertion Loss

- Better than -6 dB insertion loss from 65 GHz to 90 GHz



TDR Measurement

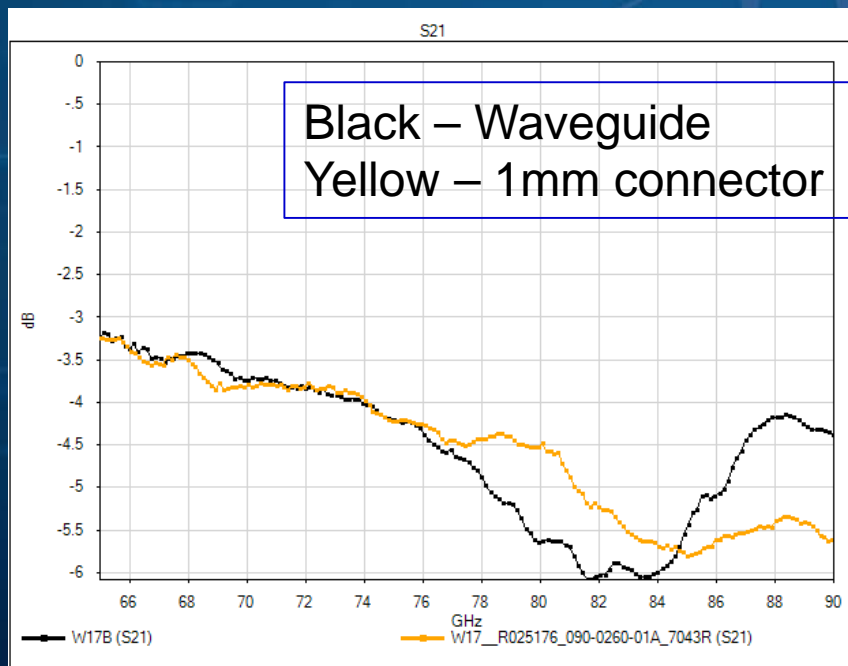
- The TDR data shows that the impedance discontinuity is less than 60 milli-rho at the waveguide to coax transition



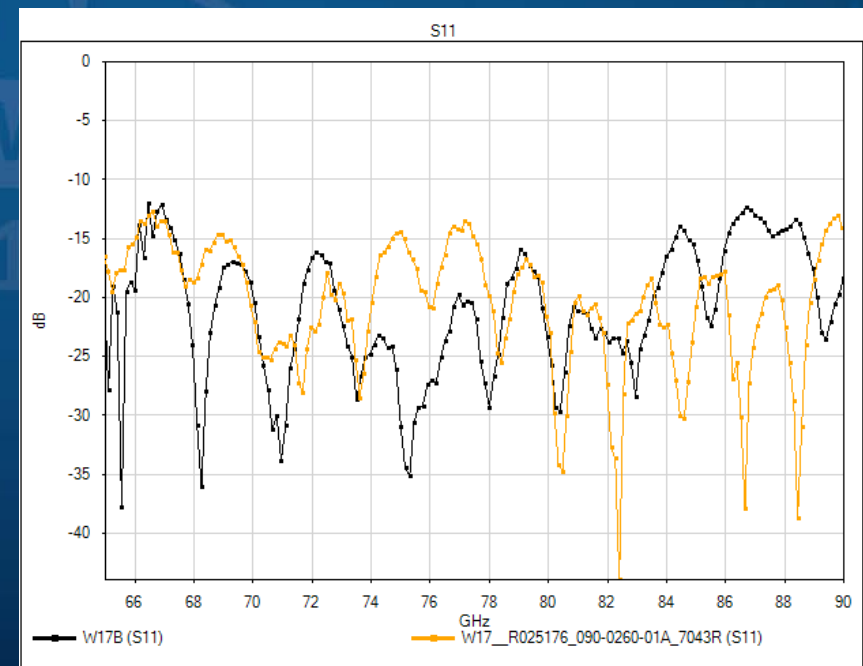
Comparison with 1mm

- Comparing with a typical probe card using 1 mm connectors, the performance is similar over the frequency range
 - 22 mm of waveguide and ~40 mm for coax
 - 1 mm connector (~13 mm long) and ~40 mm of coax

Insertion Loss



Return Loss



Next Steps

- **Continuing work to evaluate the number of cycles**
 - Our expectation is that mechanical wear should have a minimal effect
- **Evaluation of the repeatability of RF performance with dock/undocking cycles**

Summary

- **We have characterized a direct dock waveguide connector that could be used with ATE systems**
 - It meets the performance requirements for 65-90 GHz
- **The hard dock waveguide connector will work well for full production test**



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Questions?

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